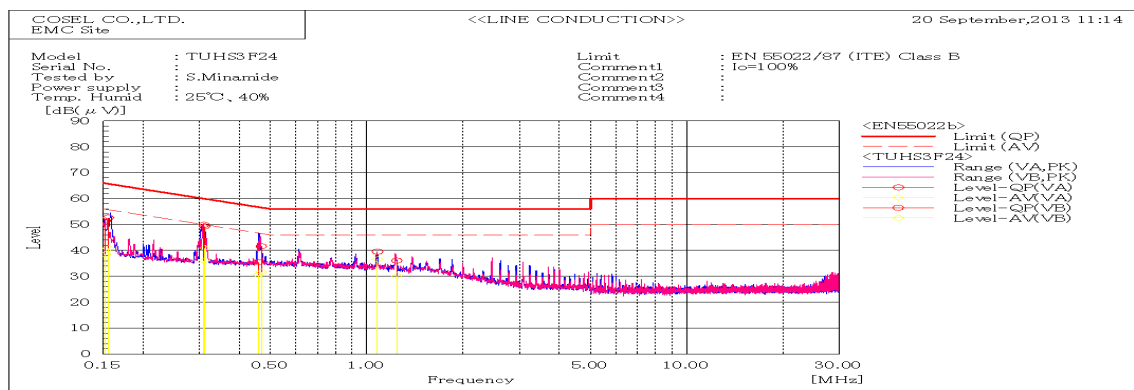


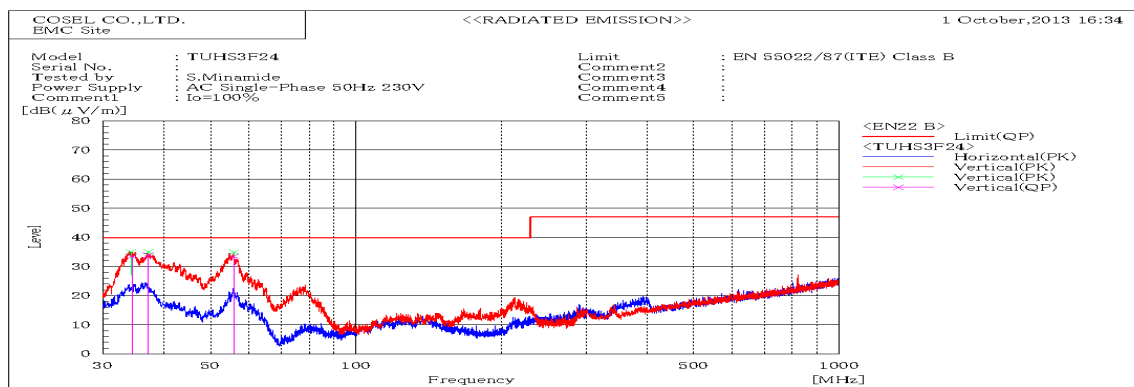
DATA SHEET

Date	16-Dec-13
Temp.	25 degreeC
Humid.	40 %RH
Tested by	S.Minamide

Model	TUHS3F24
Test	EMI Line conduction & Radiated emission



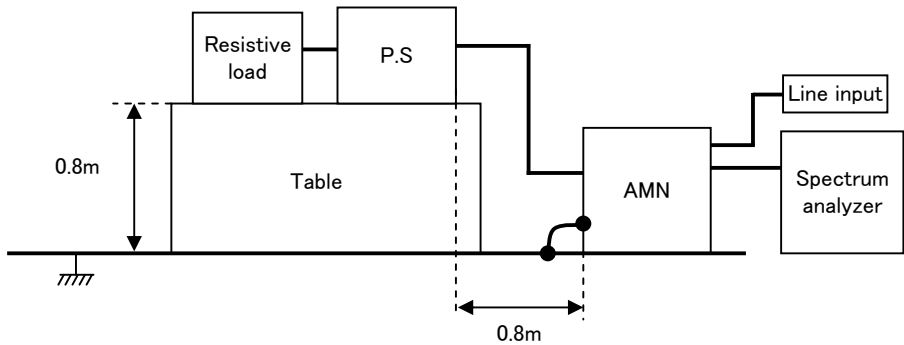
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.1522		VB	31.3	10.5	20.2	51.5	30.6	65.9	55.9	14.4	16.1	Pass	
0.15566		VA	32.4	10.1	20.2	52.6	30.3	65.7	55.7	13.1	15.7	Pass	
0.30971		VB	29.7	16.4	20.1	49.8	36.6	60.0	50.0	10.2	9.4	Pass	
0.31109		VA	29.2	11.6	20.1	49.3	31.7	59.9	49.9	10.6	14.8	Pass	
0.45699		VA	15.4	20.8	20.1	35.5	40.9	56.7	46.7	21.2	9.0	Pass	
0.46798		VB	21.5	15.9	20.1	41.6	36.0	56.5	46.5	14.9	14.0	Pass	
1.08069		VA	19.3	18.3	20.2	39.5	38.5	56.0	46.0	16.5	17.4	Pass	
1.24102		VB	15.9	20.6	20.2	36.1	40.8	56.0	46.0	19.9	14.9	Pass	



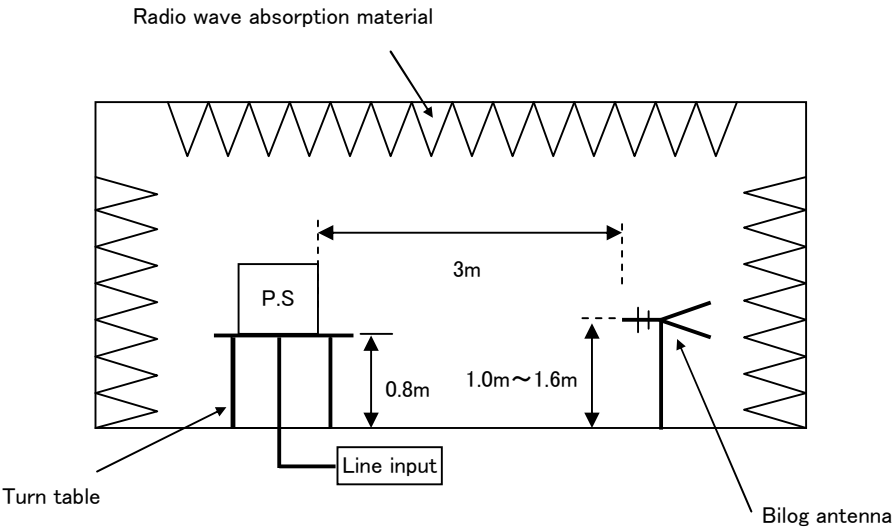
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
34.401	V	Stable	48.1		-14.6	33.5	40	6.5	Pass	103	45	
37.174	V	Stable	49		-15.1	33.9	40	6.1	Pass	100	52	
55.855	V	Stable	57.4		-23.9	33.5	40	6.5	Pass	107	50	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

Test: EMI

Model Name: TUHS3F□□

○ Photographs of Test Set-Up

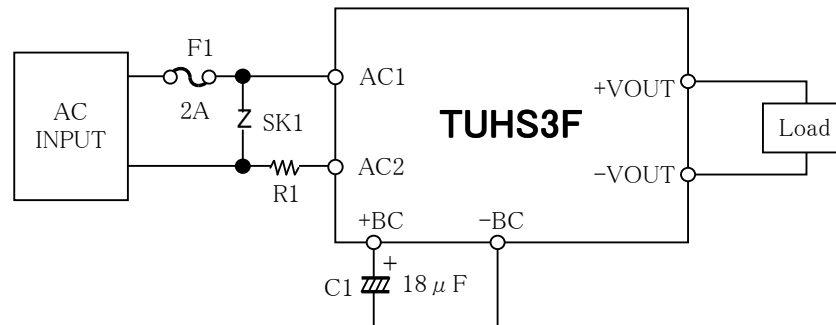
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 1K100JA (TAMURA THERMAL DEVICE)

SK1: TND10V-511K (NIPPON CHEMI-CON)

2A

10Ω

Fig.1 Testing circuitry